## Search Notes



Application/Control

10615092

Reexamination
KAWANO ET AL.

Applicant(s)/Patent Under

Examiner

Sipple IV, Edward C

**Art Unit** 

2609

## **SEARCHED**

Class	Subclass	Date	Examiner
725	105,111,120,121,124,125,126,127,131,139149,151,152	7/5/07	Edward Sipple
386	all	7/6/07	Edward Sipple

## **SEARCH NOTES**

Search Notes	Date	Examiner
Prior art consultation with examiner Hai Tran	7/5/07	Edward Sipple
Prior art consultation wit examiner Hai Tran	7/9/07	Edward Sipple

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner

U.S. Patent and Trademark Office Part of Paper No.: 20070706